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LIST OF REFERENCES CITED BY APPLICANT							APPLICANT Takeshi YOSHIDA	
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				U.S. PATENT DOCUMENTS				
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*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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Examiner

Additional References sheet(s) attached

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